		Application/Control No.	Applicant(s)/Patent Under Reexamination
Notice of References Cited		09/830,532	IWAHASHI, NAOTO
		Examiner	Art Unit	Page 1 of 1
		Thomas E Shortledge	2654	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,692,097	11-1997	Yamada et al.	704/241
	B	US-5,791,904	08-1998	Russell et al.	434/167
	C	US-4,905,287	02-1990	Segawa, Hideo	704/254
	D	US-6,108,628	08-2000	Komori et al.	704/256
	E	US-5,797,123	08-1998	Chou et al.	704/256
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hirakawa et al. "Inhertied Feature-based Similarity Measure Based on Large Semantic Hierarchy and Large Text Corpus," 1996, Proceedings of the 16th conference on Computational linguistics - Volume 1, Pages: 508 - 513
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.